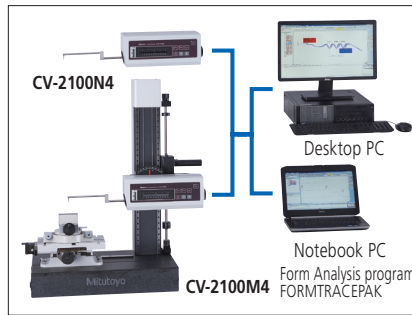


# Contracer

High precision + high functionality + high operability = Contracer

## Contracer CV-2100 SERIES 218 — Contour Measuring Instruments

**MeasurLink® ENABLED**  
Data Management Software by Mitutoyo



### SPECIFICATIONS

Model No.	CV-2100M4	CV-2100N4
Measurement range	X-axis Z1-axis (detector unit)	100 mm 50 mm
Z2-axis (column) travel range	350 mm	—
X-axis inclination angle	±45°	—
Accuracy (20 °C)	X-axis Z1-axis	±(2.5+0.02L)μm L = Measurement Length (mm) ±(2.5+0.1H)μm H = Measurement height from horizontal position within ±25 mm

Note: While the appearance of the natural stone measuring table varies according to the source, the high stability for which this material is known can always be relied upon.

\* For the CV-2100N4, a manual column stand is required (optionally available).

## Contracer CV-3200 SERIES 218 — Contour Measuring Instruments

**MeasurLink® ENABLED**  
Data Management Software by Mitutoyo



### SPECIFICATIONS

Model No.	CV-3200S4	CV-3200H4	CV-3200W4	CV-3200L4	CV-3200S8	CV-3200H8	CV-3200W8	CV-3200L8
Measuring range	X-axis Z1-axis (detector)	100 mm 60 mm (±30 mm from the horizontal)	200 mm	200 mm	200 mm	200 mm	200 mm	200 mm
Z2-axis (column) travel range	300 mm	500 mm	700 mm	300 mm	500 mm	700 mm	700 mm	700 mm
Accuracy (20 °C)	X-axis Z1-axis (detector)	±(0.8+0.01L)μm L = traverse length (mm) Wide range: 1.8 μm/100 mm Narrow range: 1.05 μm/25 mm	±(0.8+0.02L)μm L = traverse length (mm) Wide range: 4.8 μm/200 mm Narrow range: 1.3 μm/25 mm	±(0.8+0.02L)μm L = traverse length (mm) Wide range: 4.8 μm/200 mm Narrow range: 1.3 μm/25 mm	±(0.8+0.02L)μm L = traverse length (mm) Wide range: 4.8 μm/200 mm Narrow range: 1.3 μm/25 mm	±(0.8+0.02L)μm L = traverse length (mm) Wide range: 4.8 μm/200 mm Narrow range: 1.3 μm/25 mm	±(0.8+0.02L)μm L = traverse length (mm) Wide range: 4.8 μm/200 mm Narrow range: 1.3 μm/25 mm	±(0.8+0.02L)μm L = traverse length (mm) Wide range: 4.8 μm/200 mm Narrow range: 1.3 μm/25 mm
		±(1.4+2H/100)μm H = probing height from the horizontal (mm)						

Note: While the appearance of the natural stone measuring table varies according to the source, the high stability for which this material is known can always be relied upon.

**MeasurLink® ENABLED**  
Data Management Software by Mitutoyo

Products equipped with the measurement data output function can be connected to the measurement data network system MeasurLink (refer to page A-5 for details).



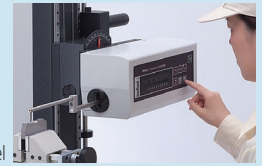
An inspection certificate is supplied as standard. Refer to page X for details.

## Contour Measuring System enabling measurement that is fast, accurate, and easy.

- The operation flow is significantly shortened by arranging the controls for stylus position change, measurement start/stop and return on the front of the drive unit.

Centralized front control panel

- Fine and coarse X-axis positioning can be performed easily by using the jog shuttle that covers the whole measuring range.



Motor-driven jog shuttle

- The quick-vertical-motion stand allows operators to swiftly and easily move the drive unit to and from the measurement height without having to push or pull (only for CV-2100M4).



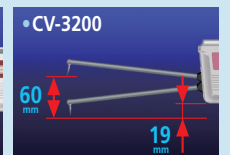
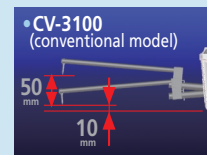
Quick-vertical-motion stand



Refer to the Contracer CV-2100 Catalog (No. E15020) for more details.

## Dramatically Improved High-Precision Contour Measuring Instruments.

- CV-3200 series are contour measuring instruments equipped with a high-precision arc scale and newly designed arm on the Z1-axis (detector). The high-precision arc scale can directly read the arc track of the stylus tip to achieve high accuracy and resolution. The new arm has extended the Z1-axis measuring range by 10 mm while reducing the chance of interference with workpieces compared to conventional models. The arm mount can be attached/detached with a single touch on the magnet joint for improved ease of operation.



Z1-axis measuring range has been extended by 10 mm.

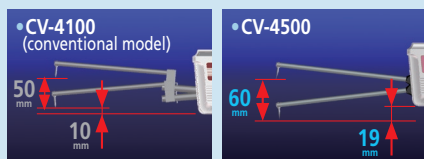
- The 700 mm Z2-axis (column) range models are new to the lineup.



An inspection certificate is supplied as standard. Refer to page X for details.

## Dramatically Improved High-Precision Contour Measuring Instruments.

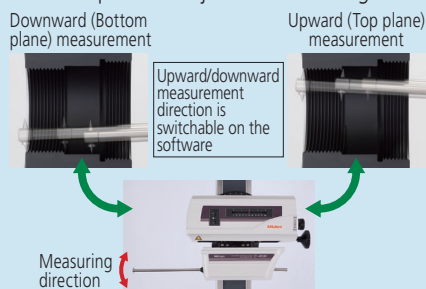
- CV-4500 series are contour measuring instruments equipped with a high-precision arc scale and newly designed arm on the Z1-axis (detector). The high-precision arc scale can directly read the arc track of the stylus tip to achieve high accuracy and resolution. The new arm has extended the Z1-axis measuring range by 10 mm while reducing the chance of interference with workpieces compared to conventional models. The arm mount can be attached/detached with a single touch on the magnet joint for improved ease of operation.



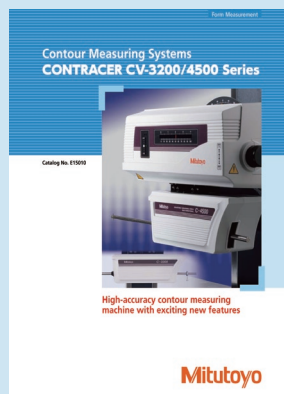
Z1-axis measuring range has been extended by 10 mm.

- The following two features have been added exclusively for the CV-4500 series:

- (1) Continuous measurement in the vertical direction (up/down) is available in combination with a double-sided conical stylus. Up/down continuous measurement data facilitates the analysis of the effective diameter of screw threads, which has been difficult to measure in the past.
- (2) The measuring force can be set in the FORMTRACEPAK software. Weight replacement and position adjustment are not required to adjust the measuring force.



- The 700 mm Z2-axis (column) range models are new to the lineup.



Refer to the Contracer CV-3200/4500 series Catalog (No. E15010) for more details.

## Contracer CV-4500 SERIES 218 — Contour Measuring Instruments



CV-4500S4

### SPECIFICATIONS

Model No.			CV-4500S4	CV-4500H4	CV-4500W4	CV-4500L4	CV-4500S8	CV-4500H8	CV-4500W8	CV-4500L8
Measuring range	X-axis	100 mm					200 mm			
	Z1-axis (detector)	60 mm (±30 mm from the horizontal)								
Z2-axis (column) travel range		300 mm	500 mm		700 mm	300 mm	500 mm		700 mm	
Z1-axis (Detector)	Scale type	Arc								
	Resolution	0.02 μm								
	Stylus up/down	Arc motion								
	Measuring direction	Forward / backward								
	Face of stylus	Vertical direction (up/down, available for continuous measurement)								
	Measuring force	10, 20, 30, 40, 50 mN (switching on the software)								
	Traceable angle	Ascent: 77°, descent: 83° (using the standard one-sided cut stylus* <sup>1</sup> provided and depending on the surface roughness)								
Drive unit	Scale type	X-axis	Separate type linear scale							
		Z2-axis (column)	ABS scale							
	Resolution	X-axis	0.05 μm							
		Z2-axis (column)	1 μm							
	Drive speed	X-axis	0 to 80 mm/s or manual operation							
		Z2-axis (column)	0 to 30 mm/s or manual operation							
	Measuring speed	X-axis	0.02, 0.05, 0.1, 0.2, 0.5, 1.0, 2.0, 5.0, 10, 20 mm/s							
	Straightness* <sup>2</sup>	X-axis	0.8 μm/100 mm				2 μm/200 mm			
Inclination range	X-axis	±45°								
Accuracy (20 °C)	X-axis	±(0.8+0.01L)μm L = traverse length (mm) Wide range: 1.8 μm/100 mm Narrow range: 1.05 μm/25 mm				±(0.8+0.02L)μm L = traverse length (mm) Wide range: 4.8 μm/200 mm Narrow range: 1.3 μm/25 mm				
	Z1-axis (detector)	±(0.8+2H/100)μm H = probing height from the horizontal (mm)								
External dimensions (W×D×H)	Main unit* <sup>3</sup>	756×482×966 mm	756×482×1166 mm	1156×482×1176 mm	1156×492×1436 mm	766×482×966 mm	766×482×1166 mm	1166×482×1176 mm	1156×492×1436 mm	
Mass	Main unit	140 kg	150 kg	220 kg	270 kg	140 kg	150 kg	220 kg	270 kg	

\*1: SPH-71 (No. 354884)

\*2: In X-axis horizontal position

\*3: Base material of the main unit is Gabbro.

Note: While the appearance of the natural stone measuring table varies according to the source, the high stability for which this material is known can always be relied upon.